

FDP75N08A

N-Channel UniFET™ MOSFET

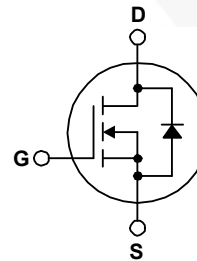
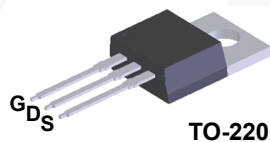
75 V, 75 A, 11 mΩ

Features

- 75 A, 75 V, $R_{DS(on)} = 11 \text{ m}\Omega$ @ $V_{GS} = 10 \text{ V}$
- Low Gate Charge (Typ. 145 nC)
- Low Crss (Typ. 86 pF)
- Fast Switching
- Improved dv/dt Capability

Description

UniFET™ MOSFET is Fairchild Semiconductor's high voltage MOSFET family based on planar stripe and DMOS technology. This MOSFET is tailored to reduce on-state resistance, and to provide better switching performance and higher avalanche energy strength. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.



Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted.

Symbol	Parameter	FDP75N08A	Unit
V_{DSS}	Drain-Source Voltage	75	V
I_D	Drain Current - Continuous ($T_C = 25^\circ\text{C}$) - Continuous ($T_C = 100^\circ\text{C}$)	75	A
		47	A
I_{DM}	Drain Current - Pulsed (Note 1)	300	A
V_{GSS}	Gate-Source Voltage	± 20	V
E_{AS}	Single Pulsed Avalanche Energy (Note 2)	1738	mJ
I_{AR}	Avalanche Current (Note 1)	75	A
E_{AR}	Repetitive Avalanche Energy (Note 1)	13.7	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	4.5	V/ns
P_D	Power Dissipation ($T_C = 25^\circ\text{C}$)	137	W
	- Derate Above 25°C	1.09	W/ $^\circ\text{C}$
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
T_L	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds	300	$^\circ\text{C}$

Thermal Characteristics

Symbol	Parameter	FDP75N08A	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	0.91	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	62.5	$^\circ\text{C}/\text{W}$

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP75N08A	FDP75N08A	TO-220	Tube	N/A	50 units

Electrical Characteristics TC = 25°C unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = 250\ \mu\text{A}$	75	--	--	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\ \mu\text{A}$, Referenced to 25°C	--	0.6	--	V/°C
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 75\text{ V}, V_{GS} = 0\text{ V}$	--	--	1	μA
		$V_{DS} = 60\text{ V}, T_C = 125^\circ\text{C}$	--	--	10	μA
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 20\text{ V}, V_{DS} = 0\text{ V}$	--	--	100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -20\text{ V}, V_{DS} = 0\text{ V}$	--	--	-100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\ \mu\text{A}$	2.0	--	4.0	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{ V}, I_D = 37.5\text{ A}$	--	9.4	11	m Ω
g_{FS}	Forward Transconductance	$V_{DS} = 40\text{ V}, I_D = 37.5\text{ A}$	--	15	--	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS} = 25\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$	--	3437	4468	pF
C_{oss}	Output Capacitance		--	738	959	pF
C_{rss}	Reverse Transfer Capacitance		--	86	129	pF
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 37.5\text{ V}, I_D = 75\text{ A},$ $R_G = 25\ \Omega$ (Note 4)	--	43	95	ns
t_r	Turn-On Rise Time		--	212	434	ns
$t_{d(off)}$	Turn-Off Delay Time		--	273	556	ns
t_f	Turn-Off Fall Time		--	147	303	ns
Q_g	Total Gate Charge	$V_{DS} = 60\text{ V}, I_D = 75\text{ A},$ $V_{GS} = 10\text{ V}$ (Note 4)	--	80	104	nC
Q_{gs}	Gate-Source Charge		--	20	--	nC
Q_{gd}	Gate-Drain Charge		--	24	--	nC
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain-Source Diode Forward Current		--	--	75	A
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current		--	--	300	A
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{ V}, I_S = 75\text{ A}$	--	--	1.4	V
t_{rr}	Reverse Recovery Time	$V_{GS} = 0\text{ V}, I_S = 75\text{ A},$ $di_F / dt = 100\text{ A}/\mu\text{s}$	--	62	--	ns
Q_{rr}	Reverse Recovery Charge		--	145	--	nC

Notes:

- 1: Repetitive rating; pulse-width limited by maximum junction temperature.
- 2: $L = 206\ \mu\text{H}, I_{AS} = 75\text{ A}, V_{DD} = 50\text{ V}, R_G = 25\ \Omega$, starting $T_J = 25^\circ\text{C}$.
- 3: $I_{SD} \leq 75\text{ A}, di/dt \leq 200\text{ A}/\mu\text{s}, V_{DD} \leq BV_{DSS}$, starting $T_J = 25^\circ\text{C}$.
- 4: Essentially independent of operating temperature typical characteristics.

Typical Performance Characteristics

Figure 1. On-Region Characteristics

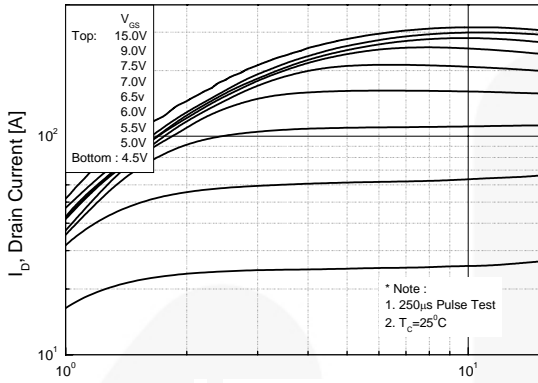


Figure 2. Transfer Characteristics

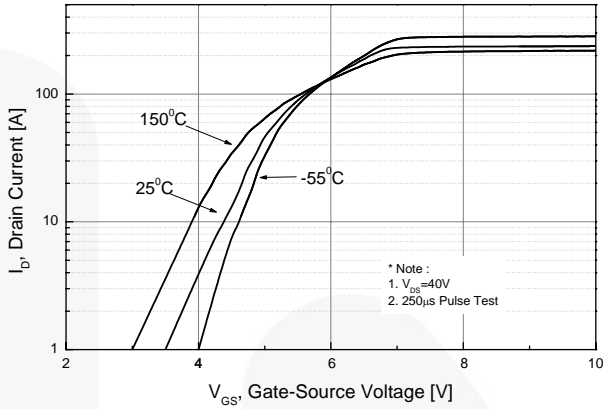


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

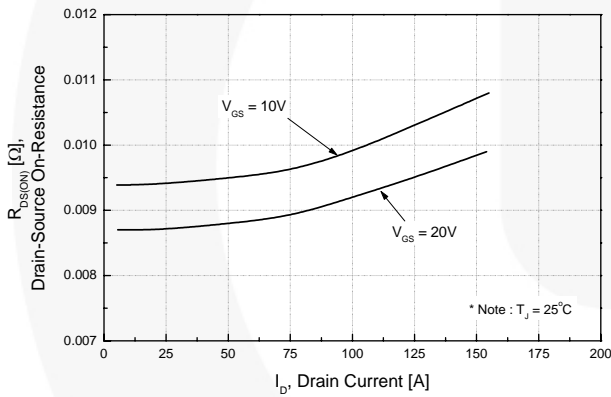


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

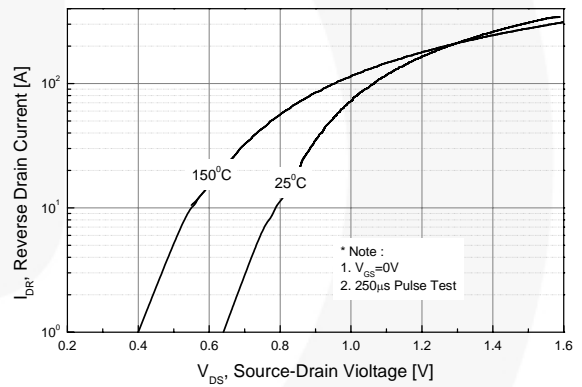


Figure 5. Capacitance Characteristics

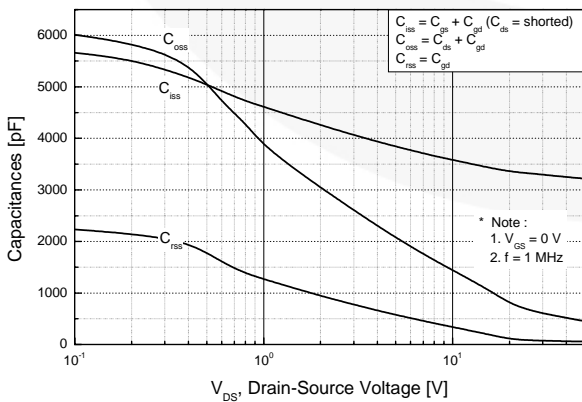
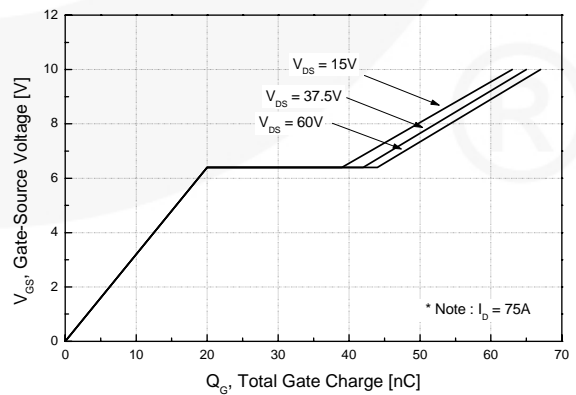


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

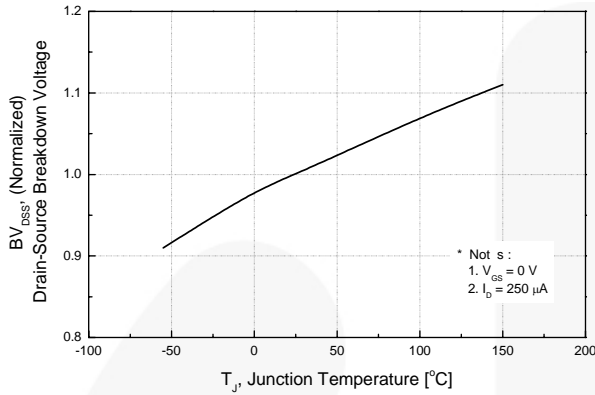


Figure 8. On-Resistance Variation vs. Temperature

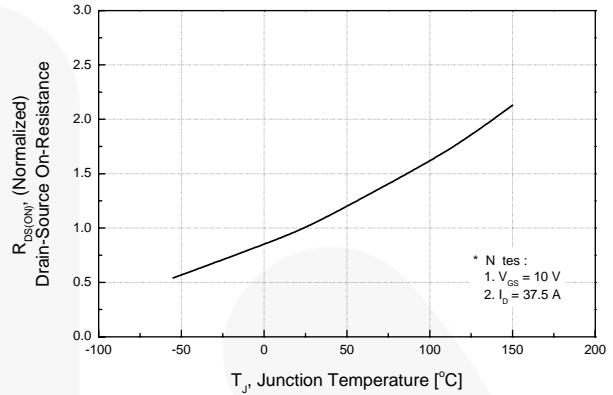


Figure 9. Maximum Safe Operating Area

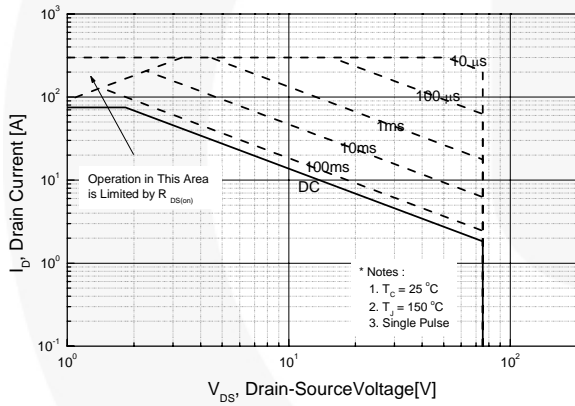


Figure 10. Maximum Drain Current vs. Case Temperature

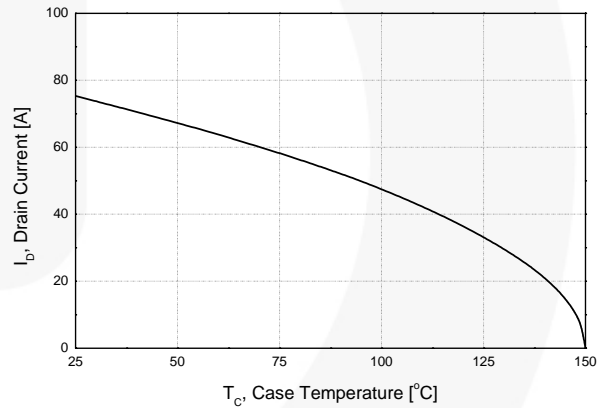


Figure 11. Transient Thermal Response Curve

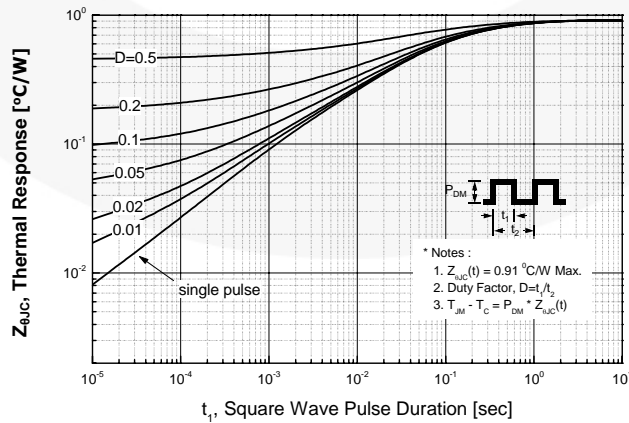


Figure 12. Gate Charge Test Circuit & Waveform

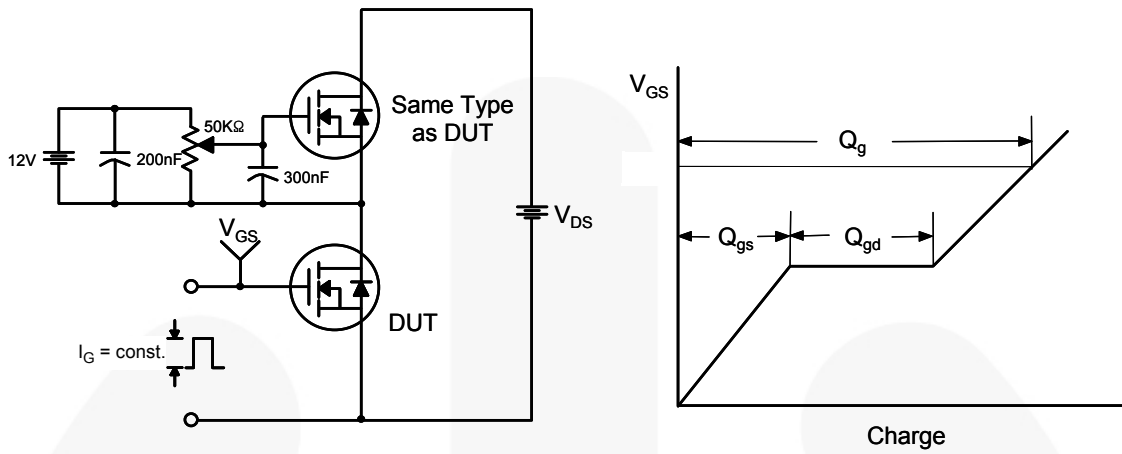


Figure 13. Resistive Switching Test Circuit & Waveforms

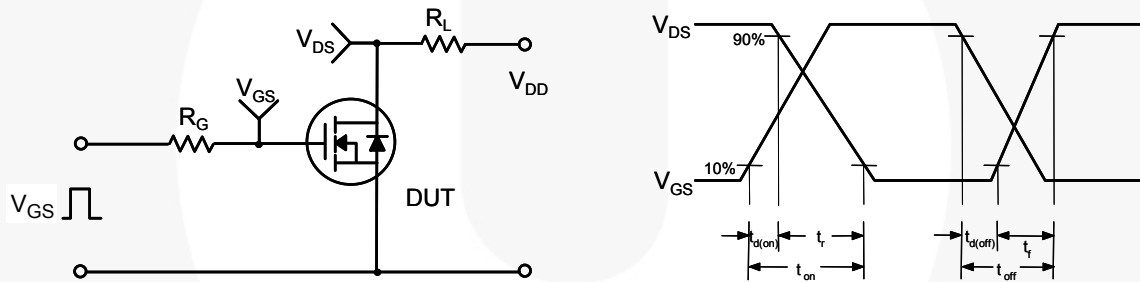


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

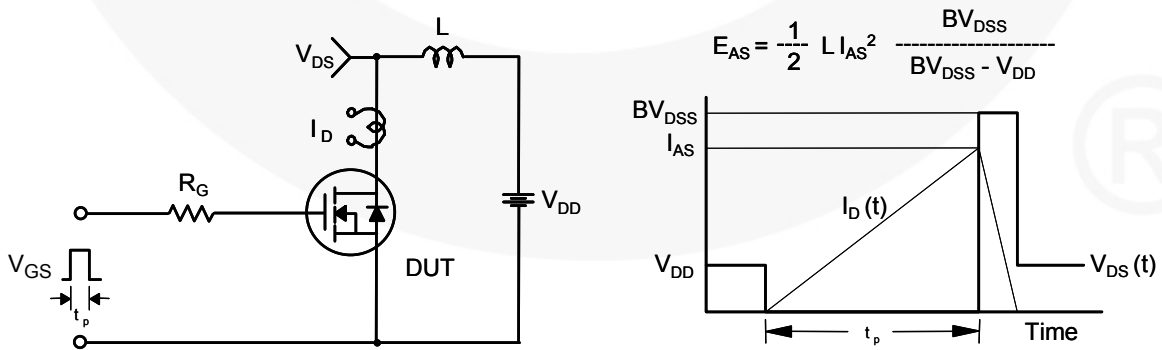
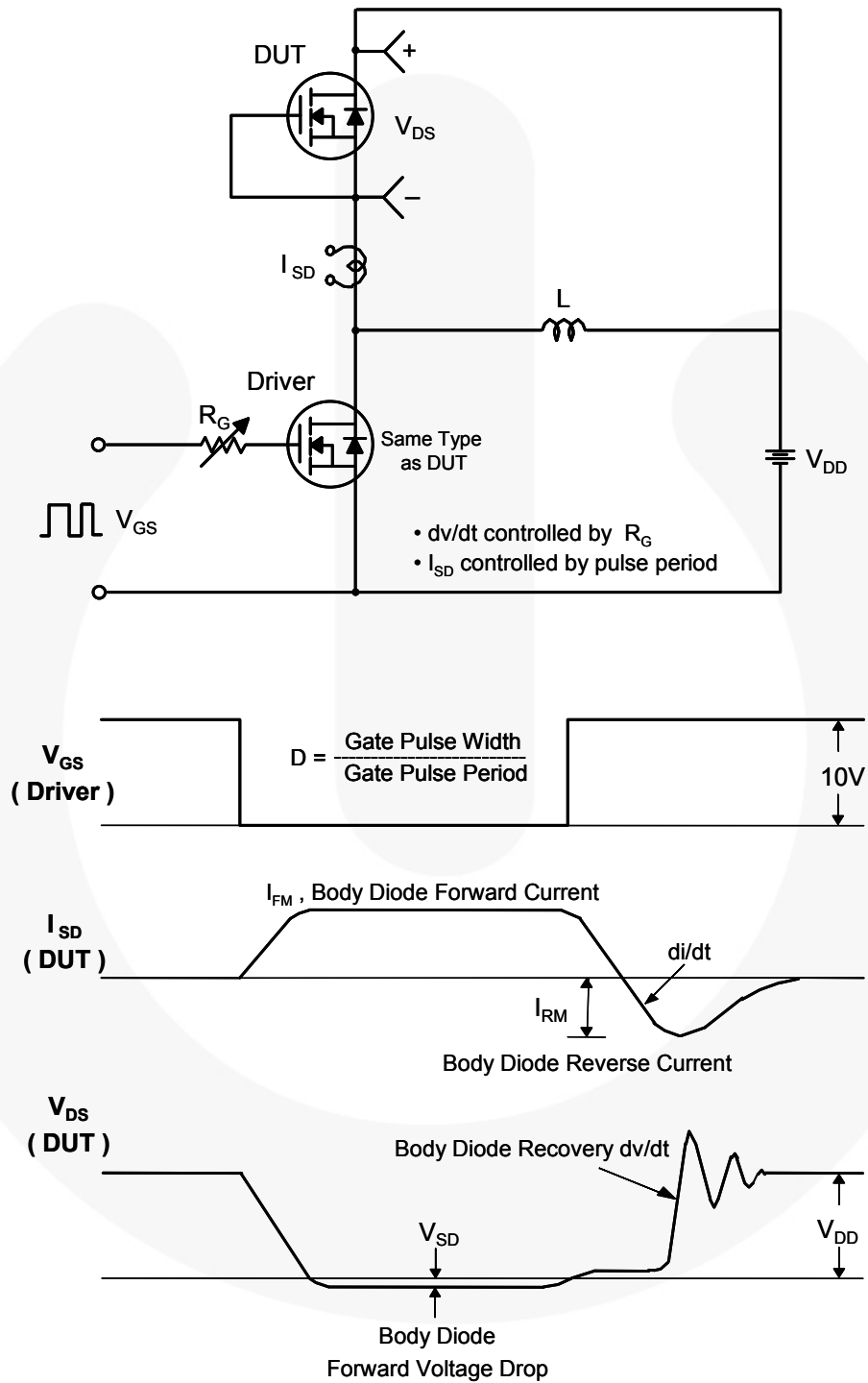


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms



Mechanical Dimensions

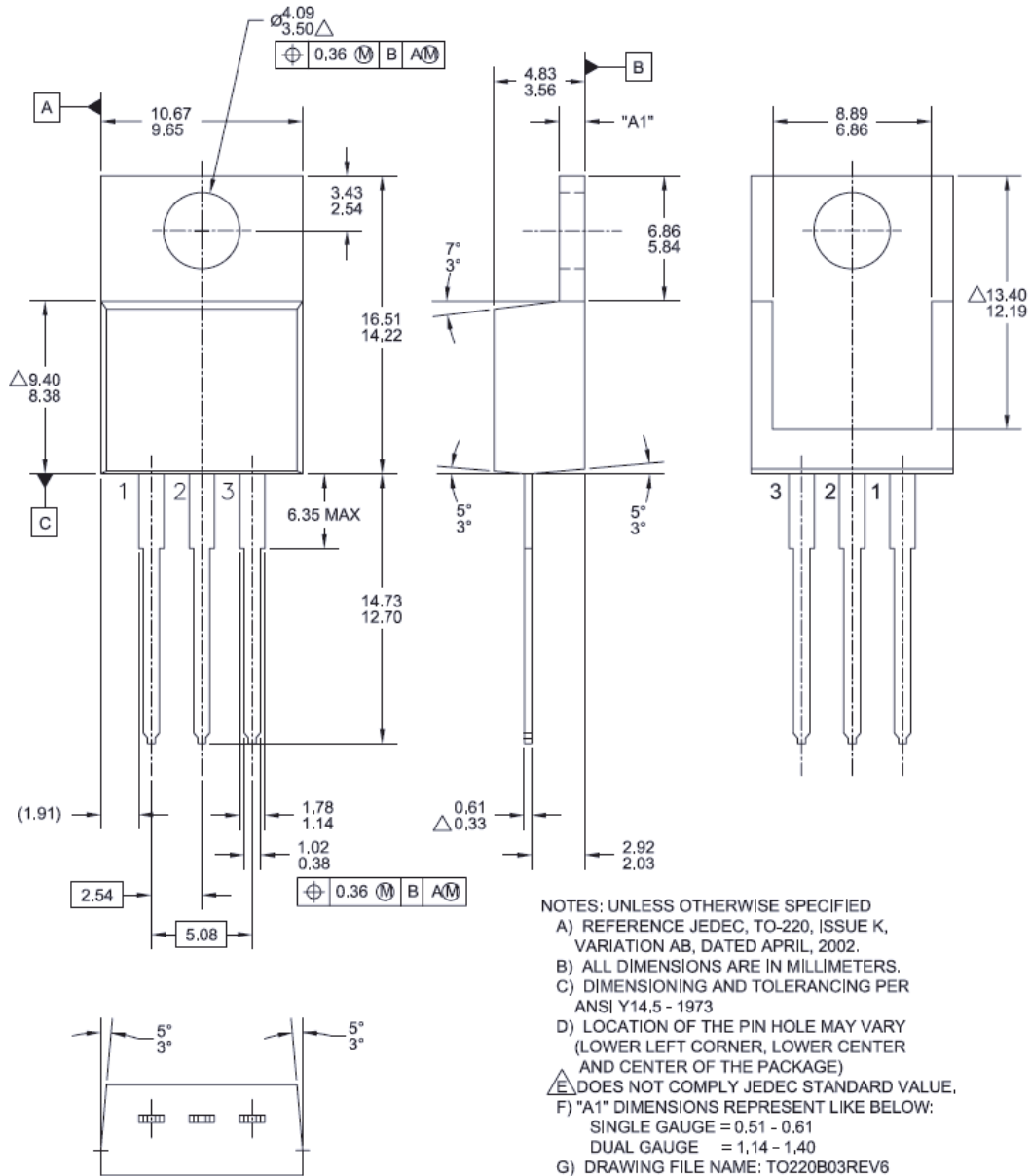


Figure 16. TO-220, Molded, 3Lead, Jedec Variation AB

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